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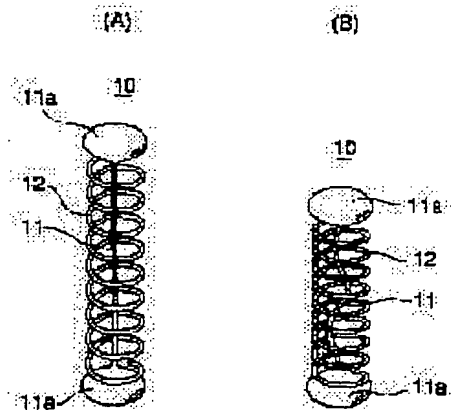
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## (54) ELECTRIC CONNECTION APPARATUS, MANUFACTURE OF CONTACT, AND SEMICONDUCTOR TESTING METHOD

## (57)Abstract:

PROBLEM TO BE SOLVED: To have good stable current transmission characteristics by providing a coil-shaped spring and a conductive member, electrically connecting first and second electrodes via a conductive member, and generating a contact pressure for the first and second electrodes.

SOLUTION: A contact 10 consists of an easily deformable conductive member 11 and a coil-shaped spring 12; the conductive member 11 is a member for transmitting a current consisting of, for example, a metallic wire or the like; and a contact pressure is provided by a metal ball 11a of both ends thereof contracting when the ball comes into contact with an external electrode such as semiconductor device. That is, when one end of the conductive member 11 comes into contact with a first electrode, and the other end comes into contact with a second electrode, the first and second electrodes are electrically connected via the conductive member 11, and a contact pressure against the first and second electrodes is generated by contraction of a spring 12. Thereby, a current transmission path is shortened, and stable electric transmission characteristics such as low resistance and low inductance can be provided.



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(54)【発明の名称】 電氣的接続装置、接触子製造方法、及び半導体試験方法

(57)【要約】

【課題】本発明は、安定した良好な電流伝達特性を有した接触子及び電氣的接続装置を提供することを目的とする。

【解決手段】電氣的接続装置は、コイル状スプリングと、該コイル状スプリングの伸縮方向に延在する変形可能な導電部材を含み、該導電部材の一端が第1の電極に接触され他端が第2の電極に接触されると、該導電部材を介して該第1の電極と該第2の電極とを電氣的に接続すると共に、該コイル状スプリングが縮むことで該第1の電極及び該第2の電極に対する接触の圧力を生成することを特徴とする。

(A)及び(B)は、本発明による接触子の実施例を示す図

